

Search Notes

Application/Control No.

09/842,531

Examiner

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Applicant(s)/Patent under
Reexamination

KIM, HYON T.

Art Unit

2142

SEARCHED

Class	Subclass	Date	Examiner
ABOVE	UPDATED	1/12/2007	HN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST search updated (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) (see search history printout report)	1/12/2007	HN